

Contents of Volume 2

V. LATTICE LOCATION AND DECHANNELING IN DISORDERED CRYSTALS

Analysis Problems in Lattice Location Studies	497
H.D. Carstanjen	
Multi-String Statistical Equilibrium Calculation of Scattering Yield for Foreign Atom Location Using Channeling Effect	517
K. Komaki	
Ion Channeling Studies of the Lattice Location of Inter- stitial Impurities: Hydrogen in Metals	527
S.T. Picraux	
Depth Distribution of Damage Obtained by Rutherford Backscattering Combined with Channeling	539
R. Behrisch, J. Roth	
Helium Trapping in Aluminum and Sintered Aluminum Powders . .	567
S.K. Das, M. Kaminsky, T. Rossing	
Helium Re-Emission and Surface Deformation in Niobium During Multiple Temperature Helium Implantation	575
W. Bauer, G.J. Thomas	

Studies on Compound Thin Film Semiconductors by Ion Beam and Electron Microscopy Techniques	585
S.U. Campisano, G. Foti, E. Rimini, G. Vitali, C. Corsi	
Energy Dependence of Channeling Analysis in Implantation Damaged Al.	597
E. Rimini, S.U. Campisano, G. Foti, P. Baeri, S.T. Picraux	
Characterization of Reordered (001) Au Surfaces by the Combined Techniques of Positive Ion Channeling Spectroscopy (PICS), LEED-AES, and Computer Simulation	607
B.R. Appleton, D.M. Zehner, T.S. Noggle, J.W. Miller, O.E. Schow III, L.H. Jenkins, J.H. Barrett	
Proton Channeling Applied to the Study of Thermal Disorder in AgBr	627
M. Roulet, C. Jaccard, H. Huber	
Neon-Ion Implantation Damage Gettering of Heavy Metal Impurities in Silicon	635
Shanghai Institute of Metallurgy, Chinese Academy of Sciences, Shanghai Institute of Nuclear Research	

VI. RELATED TECHNIQUES

A New Scanning Ion Microscope for Surface and In-Depth Analysis	649
K. Wittmaack	
Sputtering of Thin Films in an Ion Microprobe	659
W.O. Hofer, H. Liebl	
Xe ⁺ Ion Beam Induced Secondary Ion (Si ⁺) Yield from Si-Metal Interfaces	665
T. Narusawa, T. Satake, S. Komiya, A. Shimizu, M. Iwami, A. Hiraki	
Surface Analysis of Ion Bombarded Metal Foils by XPS	675
E. Henrich, H.J. Schmidt	

Chemical Reaction Enhancement and Damage Rate of Surface Layer Bombarded with Inert Ion Beams	685
T. Tsurushima, H. Tanoue	

VII. ION INDUCED X-RAY SPECTROSCOPY

Progress in the Description of Ion Induced X-Ray Production; Theory and Implication for Analysis	695
F. Folkmann	
K-Shell Ionization of Boron Induced by Light Ions Bombardment	719
K. Kawatsura, K. Ozawa, F. Fujimoto, M. Terasawa	
Effect of Channeling on Impurity Analysis by Charged Particle Induced X-Rays	727
P.B. Price, B.E. Cooke, G.T. Ewan, J.L. Whitton	
Depth Profiling with Ion Induced X-Rays	735
L.C. Feldman, P.J. Silverman	
Sensitivity in Trace Element Analysis of Thick Samples Using Proton Induced X-Rays	747
F. Folkmann	
Review of Trace Analysis by Ion Induced X-Rays	759
J.F. Ziegler	
The Use of Proton Induced X-Rays to Monitor the Near Surface Composition of Catalysts	773
J.A. Cairns, A. Lurio, J.F. Ziegler, D.F. Holloway, J. Cookson	
Application of Proton-Induced X-Ray Emission to Elemental Analysis of Oligo-Elements in Human Lymphocytes	785
M.C. Bonnet, J.P. Thomas, H. Betuel, M. Fallavier, S. Marsaud	
Elemental Analysis of Biological Samples Using Deuteron Induced X-Rays and Charged Particles	795
L. Amtén, L. Glantz, B. Morenius, J. Pihl, B. Sundqvist	

Suppression of Radioactive Background in Ion Induced X-Ray Analysis	803
H. Sobiesiak, D. Heck, F. Käppler	

VIII. NUCLEAR REACTIONS

Depth Profiling of Hydrogen and Helium Isotopes in Solids by Nuclear Reaction Analysis	811
J. Böttiger, S.T. Picraux, N. Rud	

Achievable Depth Resolution in Profiling Light Atoms by Nuclear Reactions	821
W. Eckstein, R. Behrisch, J. Roth	

Depth Profiling of Deuterons in Metals at Large Implantation Depths Using the Nuclear Reaction Technique . . .	831
M. Hufschmidt, W. Möller, V. Heintze, D. Kamke	

Gas Reemission and Blister Formation on Nickel Surfaces During High Energy Deuteron Bombardment	841
W. Möller, Th. Pfeiffer, D. Kamke	

Unfolding Techniques for the Determination of Distribution Profiles from Resonance Reaction Gamma-Ray Yields	851
D.J. Land, D.G. Simons, J.G. Brennan, M.D. Brown	

Z ₂ Dependence of the Electronic Stopping Power of 800 keV ¹⁴ N ⁺ Ions in Targets from Carbon Through Molybdenum	863
D.G. Simons, D.J. Land, J.G. Brennan, M.D. Brown	

Sensitivity of Fluorine Detection in Different Matrices and at Different Depths Through the ¹⁹ F(p,αγ) ¹⁶ O Reaction	873
M.A. Chaudhri, G. Burns, J.L. Rouse, B.M. Spicer	

Ion Beam Analysis Techniques in Corrosion Science	885
G. Dearnaley	

Quantitative Measurement of Light Element Profiles in Thick Corrosion Films on Steels, Using the Harwell Nuclear Microbeam	901
C.R. Allen, G. Dearnaley, N.E.W. Hartley	
Nuclear Microprobe Analysis of Reactor Materials	913
J.W. McMillan, T.B. Pierce	
Analysis of Microgram Quantities of Aluminum in Germanium .	925
I.V. Mitchell, W.N. Lennard	
Analysis of Fluorine by Nuclear Reactions and Application to Human Dental Enamel	933
J. Stroobants, F. Bodart, G. Deconninck, G. Demoriter, G. Nicolas	
Determination of Nitrogen Depth Distributions in Cereals Using the $^{14}\text{N}(\text{d},\text{p}_0)^{15}\text{N}$ Reaction	945
B. Sundqvist, L. Gönczi, I. Koersner, R. Bergman, U. Lindh	
Experimental Measurements, Mathematical Analysis and Partial Deconvolution of the Asymmetrical Response of Surface Barrier Detectors to MeV ^4He , ^{12}C , ^{14}N , ^{16}O Ions	953
G. Amsel, C. Cohen, A. L'Hoir	
Experimental Study of the Stopping Power and Energy Stragglings of MeV ^4He , ^{12}C , ^{14}N , ^{16}O Ions in Amorphous Aluminium Oxide	965
A. L'Hoir, C. Cohen, G. Amsel	
AUTHOR INDEX	977
SUBJECT INDEX	981